

PIC24HJ256GPX06A/X08A/X10A Family Silicon Errata and Data Sheet Clarification

The PIC24HJ256GPX06A/X08A/X10A family devices that you have received conform functionally to the current Device Data Sheet (DS70592**B**), except for the anomalies described in this document.

The silicon issues discussed in the following pages are for silicon revisions with the Device and Revision IDs listed in Table 1. The silicon issues are summarized in Table 2.

The errata described in this document will be addressed in future revisions of the PIC24HJ256GPX06A/X08A/X10A silicon.

Note: This document summarizes all silicon errata issues from all revisions of silicon, previous as well as current. Only the issues indicated in the last column of Table 2 apply to the current silicon revision (A3).

Data Sheet clarifications and corrections start on page 5, following the discussion of silicon issues.

The silicon revision level can be identified using the current version of MPLAB[®] IDE and Microchip's programmers, debuggers and emulation tools, which are available at the Microchip corporate web site (www.microchip.com).

For example, to identify the silicon revision level using MPLAB IDE in conjunction with MPLAB ICD 2 or PICkit™ 3:

- Using the appropriate interface, connect the device to the MPLAB ICD 2 programmer/debugger or PICkit 3.
- From the main menu in MPLAB IDE, select <u>Configure>Select Device</u>, and then select the target part number in the dialog box.
- 3. Select the MPLAB hardware tool (<u>Debugger>Select Tool</u>).
- Perform a "Connect" operation to the device (<u>Debugger>Connect</u>). Depending on the development tool used, the part number and Device Revision ID value appear in the **Output** window.

Note: If you are unable to extract the silicon revision level, please contact your local Microchip sales office for assistance.

The Device and Revision ID values for the various PIC24HJ256GPX06A/X08A/X10A silicon revisions are shown in Table 1.

TABLE 1: SILICON DEVREV VALUES

Part Number	Device ID ⁽¹⁾	Revision ID for Silicon Revision ⁽²⁾		
	Device ID.	A2	А3	
PIC24HJ256GP206A	0x0771			
PIC24HJ256GP210A	0x0773	0x3002	0x3003	
PIC24HJ256GP610A	0x077B			

- **Note 1:** The Device and Revision IDs (DEVID and DEVREV) are located at the last two implemented addresses in program memory.
 - **2:** Refer to the "dsPIC33F/PIC24H Flash Programming Specification" (DS70152) for detailed information on Device and Revision IDs for your specific device.

TABLE 2: SILICON ISSUE SUMMARY

Module Feature		Item Number	Issue Summary	Affected Revisions ⁽¹⁾	
		Humber		A2	А3
ECAN	WAKIF bit	1.	The WAKIF bit in the CxINTF register cannot be cleared by software instruction after the device is interrupted from Sleep due to activity on the CAN bus.	Х	Х
ECAN	DMA	2.	alse DMA Error Traps may be generated in applications that erform both transmissions and receptions using ECAN with MA.		
UART	Break Characters	3.	The UART module will not generate consecutive break characters.	Х	Х
ADC	DONE bit	4.	The ADC Conversion Status bit (DONE) does not work when External Interrupt is selected as the ADC trigger source.	Х	Х
SPI	TBF bit	5.	Writing to the SPIBUF register as soon as the TBF bit is cleared will cause the SPI module to ignore the written data.	Х	Х
DMA Controller	CPU Write Collision Detection	6.	DMA CPU write collisions will not be detected.		Х
ADC	Current Consumption in Sleep Mode	7.	If the ADC module is in an enabled state when the device enters Sleep Mode, the power-down current (IPD) of the device may exceed the device data sheet specifications.	Х	Х
All	150°C Operation	8.	Affected revisions of silicon only support 140°C operation instead of 150°C for extended operating temperature.	Х	Х

Note 1: Only those issues indicated in the last column apply to the current silicon revision.

Silicon Errata Issues

Note:

This document summarizes all silicon errata issues from all revisions of silicon, previous as well as current. Only the issues indicated by the shaded column in the following tables apply to the current silicon revision (A3).

1. Module: ECAN

The WAKIF bit in the CxINTF register cannot be cleared by software instruction after the device is interrupted from Sleep due to activity on the CAN bus

When the device wakes up from Sleep due to CAN bus activity, the ECAN module is placed in operational mode. The ECAN Event interrupt occurs due to the WAKIF flag. Trying to clear the flag in the Interrupt Service Routine (ISR) may not clear the flag. The WAKIF bit being set will not cause repetitive Interrupt Service Routine execution.

Work around

Although the WAKIF bit does not clear, the device Sleep and ECAN Wake functions continue to work as expected. If the ECAN event is enabled, the CPU will enter the Interrupt Service Routine due to the WAKIF flag getting set. The application can maintain a secondary flag, which tracks the device Sleep and Wake events.

Affected Silicon Revisions

A2	А3			
Х	Х			

2. Module: ECAN

In user applications that perform both transmissions and receptions using ECAN with DMA, intermittent DMA Write Collisions might get generated, resulting in the generation of DMA Error Traps. The ECAN messages would be transmitted and received correctly even when these DMA Error Traps occur.

Work around

Within the DMA Error Trap service routine in the application software, read the DMACS0 register and inspect the two XWCOLn (n = 0, 1, ...,7) bits corresponding to the DMA channels being used for ECAN transmission and reception.

For example, if DMA Channel 1 is used for ECAN Reception and DMA Channel 2 is used for ECAN Transmission, inspect the XWCOL1 and XWCOL2 bits. If either of these bits is found to be set, clear the DMACERR bit in the INTCON1 register and return from the DMA Error Trap service routine.

Affected Silicon Revisions

A2	А3			
Χ				

3. Module: UART

The UART module will not generate consecutive break characters. Trying to perform a back-to-back Break character transmission will cause the UART module to transmit the dummy character used to generate the first Break character instead of transmitting the second Break character. Break characters are generated correctly if they are followed by non-Break character transmission.

Work around

None.

Affected Silicon Revisions

A2	А3			
Χ	Χ			

4. Module: ADC

The ADC Conversion Status (DONE) bit (ADxCON1<0>) does not indicate completion of conversion when External Interrupt is selected as the ADC trigger source (ADxCON1<SSRC> = 1).

Work around

Use an ADC interrupt or poll ADxIF bit in the IFSx registers to determine the completion of conversion.

Affected Silicon Revisions

A2	А3			
Χ	Χ			

5. Module: SPI

Writing to the SPIxBUF register as soon as the TBF bit is cleared will cause the SPI module to ignore the written data. Applications that use SPI with DMA are not affected by this erratum.

Work around

After the TBF bit is cleared, wait for a minimum duration of one SPI clock before writing to the SPIxBUF register.

Alternately, do one of the following:

- Poll the RBF bit and wait for it to get set before writing to the SPIxBUF register
- Poll the SPI Interrupt flag and wait for it to get set before writing to the SPIxBUF register
- · Use an SPI Interrupt Service Routine
- Use DMA

Affected Silicon Revisions

A2	А3			
Χ	Х			

6. Module: DMA Controller

DMA CPU write collisions will not be detected, and the corresponding XWCOLn bit (n = 0, 1, ..., 7) will not be set. As a result, a CPU write collision event will not generate a DMA Error Trap.

Work around

None. Before writing to any memory location in DMA RAM, ensure that none of the enabled DMA channels is using the same memory location for data transfers from a peripheral.

Affected Silicon Revisions

A2	А3			
	Х			

7. Module: ADC

If the ADC module is in an enabled state when the device enters Sleep mode as a result of executing a PWRSAV #0 instruction, the device power-down current (IPD) may exceed the specifications listed in the device data sheet. This may happen even if the ADC module is disabled by clearing the ADON bit prior to entering Sleep mode.

Work around

In order to remain within the IPD specifications listed in the device data sheet, the user software must completely disable the ADC module by setting the ADC Module Disable bit in the corresponding Peripheral Module Disable register (PMDx), prior to executing a PWRSAV #0 instruction.

Affected Silicon Revisions

A2	А3			
Χ	Х			

8. Module: All

The affected silicon revisions listed below are not warranted for operation at 150°C.

Work around

Only use the affected revisions of silicon for Hi-Temp operating range from -40°C to +140°C.

Affected Silicon Revisions

A2	А3			
Х	Х			

Data Sheet Clarifications

The following typographic corrections and clarifications are to be noted for the latest version of the device data sheet (DS70592**B**):

Note: Corrections are shown in **bold**. Where possible, the original bold text formatting has been removed for clarity.

1. Module: DC Characteristics: I/O Pin Input Specifications

The maximum value for parameter DI19 (VIL specifications for SDAx and SCLx pins) was stated incorrectly in Table 24-9 of the current device data sheet. Also, parameters DI28 and DI29 (VIH specifications for SDAx and SCLx pins) were not stated. The correct values are shown in bold type in Table 3.

TABLE 3: DC CHARACTERISTICS: I/O PIN INPUT SPECIFICATIONS

DC CHA	RACTER	ISTICS	Standard Operating Conditions: 3.0V to 3.6V (unless otherwise stated) Operating temperature -40°C ≤TA ≤+85°C for Industrial -40°C ≤TA ≤+125°C for Extended				
Param No.	I Symbol I Characteristic			Тур	Max	Units	Conditions
	VIL	Input Low Voltage					
DI18		SDAx, SCLx	Vss	_	0.3 VDD	V	SMBus disabled
DI19		SDAx, SCLx	Vss	_	0.8	V	SMBus enabled
	VIH	Input High Voltage					
DI28		SDAx, SCLx	0.7 VDD	_	5.5	٧	SMBus disabled
DI29		SDAx, SCLx	2.1	_	5.5	V	SMBus enabled

APPENDIX A: REVISION HISTORY

Rev A Document (9/2009)

Initial release of this document; issued for revision A2 silicon.

Includes silicon issues 1-2 (ECAN), 3 (UART), 4 (ADC) and 5 (SPI).

Rev B Document (12/2009)

Added silicon issue 6 (DMA Controller).

Rev C Document (6/2010)

Added silicon issue 7 (ADC) and data sheet clarification 1 (DC Characteristics: I/O Pin Input Specifications).

Rev D Document (9/2010)

Added silicon issue 8 (All).

Note the following details of the code protection feature on Microchip devices:

- Microchip products meet the specification contained in their particular Microchip Data Sheet.
- Microchip believes that its family of products is one of the most secure families of its kind on the market today, when used in the intended manner and under normal conditions.
- There are dishonest and possibly illegal methods used to breach the code protection feature. All of these methods, to our
 knowledge, require using the Microchip products in a manner outside the operating specifications contained in Microchip's Data
 Sheets. Most likely, the person doing so is engaged in theft of intellectual property.
- Microchip is willing to work with the customer who is concerned about the integrity of their code.
- Neither Microchip nor any other semiconductor manufacturer can guarantee the security of their code. Code protection does not mean that we are guaranteeing the product as "unbreakable."

Code protection is constantly evolving. We at Microchip are committed to continuously improving the code protection features of our products. Attempts to break Microchip's code protection feature may be a violation of the Digital Millennium Copyright Act. If such acts allow unauthorized access to your software or other copyrighted work, you may have a right to sue for relief under that Act.

Information contained in this publication regarding device applications and the like is provided only for your convenience and may be superseded by updates. It is your responsibility to ensure that your application meets with your specifications. MICROCHIP MAKES NO REPRESENTATIONS OR WARRANTIES OF ANY KIND WHETHER EXPRESS OR IMPLIED, WRITTEN OR ORAL, STATUTORY OR OTHERWISE, RELATED TO THE INFORMATION, INCLUDING BUT NOT LIMITED TO ITS CONDITION, QUALITY, PERFORMANCE, MERCHANTABILITY OR FITNESS FOR PURPOSE. Microchip disclaims all liability arising from this information and its use. Use of Microchip devices in life support and/or safety applications is entirely at the buyer's risk, and the buyer agrees to defend, indemnify and hold harmless Microchip from any and all damages, claims, suits, or expenses resulting from such use. No licenses are conveyed, implicitly or otherwise, under any Microchip intellectual property rights.

Trademarks

The Microchip name and logo, the Microchip logo, dsPIC, Keeloq, Keeloq logo, MPLAB, PIC, PICmicro, PICSTART, PIC³² logo, rfPIC and UNI/O are registered trademarks of Microchip Technology Incorporated in the U.S.A. and other countries.

FilterLab, Hampshire, HI-TECH C, Linear Active Thermistor, MXDEV, MXLAB, SEEVAL and The Embedded Control Solutions Company are registered trademarks of Microchip Technology Incorporated in the U.S.A.

Analog-for-the-Digital Age, Application Maestro, CodeGuard, dsPICDEM, dsPICDEM.net, dsPICworks, dsSPEAK, ECAN, ECONOMONITOR, FanSense, HI-TIDE, In-Circuit Serial Programming, ICSP, Mindi, MiWi, MPASM, MPLAB Certified logo, MPLIB, MPLINK, mTouch, Omniscient Code Generation, PICC, PICC-18, PICDEM, PICDEM.net, PICkit, PICtail, REAL ICE, rfLAB, Select Mode, Total Endurance, TSHARC, UniWinDriver, WiperLock and ZENA are trademarks of Microchip Technology Incorporated in the U.S.A. and other countries.

SQTP is a service mark of Microchip Technology Incorporated in the U.S.A.

All other trademarks mentioned herein are property of their respective companies.

© 2010, Microchip Technology Incorporated, Printed in the U.S.A., All Rights Reserved.

Printed on recycled paper.

ISBN: 978-1-60932-493-3

QUALITY MANAGEMENT SYSTEM

CERTIFIED BY DNV

ISO/TS 16949:2002

Microchip received ISO/TS-16949:2002 certification for its worldwide headquarters, design and wafer fabrication facilities in Chandler and Tempe, Arizona; Gresham, Oregon and design centers in California and India. The Company's quality system processes and procedures are for its PIC® MCUs and dsPIC® DSCs, KEELOQ® code hopping devices, Serial EEPROMs, microperipherals, nonvolatile memory and analog products. In addition, Microchip's quality system for the design and manufacture of development systems is ISO 9001:2000 certified.



Worldwide Sales and Service

AMERICAS

Corporate Office 2355 West Chandler Blvd.

Chandler, AZ 85224-6199 Tel: 480-792-7200 Fax: 480-792-7277 Technical Support:

http://support.microchip.com

Web Address: www.microchip.com

Atlanta

Duluth, GA Tel: 678-957-9614 Fax: 678-957-1455

Boston

Westborough, MA Tel: 774-760-0087 Fax: 774-760-0088

Chicago Itasca. IL

Tel: 630-285-0071 Fax: 630-285-0075

Cleveland

Independence, OH Tel: 216-447-0464 Fax: 216-447-0643

Dallas

Addison, TX Tel: 972-818-7423 Fax: 972-818-2924

Detroit

Farmington Hills, MI Tel: 248-538-2250 Fax: 248-538-2260

Kokomo

Kokomo, IN Tel: 765-864-8360 Fax: 765-864-8387

Los Angeles

Mission Viejo, CA Tel: 949-462-9523 Fax: 949-462-9608

Santa Clara

Santa Clara, CA Tel: 408-961-6444 Fax: 408-961-6445

Toronto

Mississauga, Ontario, Canada

Tel: 905-673-0699

Fax: 905-673-6509

ASIA/PACIFIC

Asia Pacific Office

Suites 3707-14, 37th Floor Tower 6, The Gateway Harbour City, Kowloon

Hong Kong Tel: 852-2401-1200

Fax: 852-2401-3431

Australia - Sydney

Tel: 61-2-9868-6733 Fax: 61-2-9868-6755

China - Beijing

Tel: 86-10-8528-2100 Fax: 86-10-8528-2104

China - Chengdu

Tel: 86-28-8665-5511 Fax: 86-28-8665-7889

China - Chongqing

Tel: 86-23-8980-9588 Fax: 86-23-8980-9500

China - Hong Kong SAR

Tel: 852-2401-1200 Fax: 852-2401-3431

China - Nanjing

Tel: 86-25-8473-2460 Fax: 86-25-8473-2470

China - Qingdao

Tel: 86-532-8502-7355 Fax: 86-532-8502-7205

China - Shanghai

Tel: 86-21-5407-5533 Fax: 86-21-5407-5066

China - Shenyang

Tel: 86-24-2334-2829 Fax: 86-24-2334-2393

China - Shenzhen

Tel: 86-755-8203-2660 Fax: 86-755-8203-1760

China - Wuhan

Tel: 86-27-5980-5300 Fax: 86-27-5980-5118

China - Xian

Tel: 86-29-8833-7252 Fax: 86-29-8833-7256

China - Xiamen

Tel: 86-592-2388138 Fax: 86-592-2388130

China - Zhuhai Tel: 86-756-3210040

Fax: 86-756-3210049

ASIA/PACIFIC

India - Bangalore

Tel: 91-80-3090-4444 Fax: 91-80-3090-4123

India - New Delhi

Tel: 91-11-4160-8631 Fax: 91-11-4160-8632

India - Pune

Tel: 91-20-2566-1512 Fax: 91-20-2566-1513

Japan - Yokohama

Tel: 81-45-471- 6166 Fax: 81-45-471-6122

Korea - Daegu

Tel: 82-53-744-4301 Fax: 82-53-744-4302

Korea - Seoul

Tel: 82-2-554-7200 Fax: 82-2-558-5932 or 82-2-558-5934

Malaysia - Kuala Lumpur

Tel: 60-3-6201-9857 Fax: 60-3-6201-9859

Malaysia - Penang

Tel: 60-4-227-8870 Fax: 60-4-227-4068

Philippines - Manila

Tel: 63-2-634-9065 Fax: 63-2-634-9069

Singapore

Tel: 65-6334-8870 Fax: 65-6334-8850

Taiwan - Hsin Chu

Tel: 886-3-6578-300 Fax: 886-3-6578-370

Taiwan - Kaohsiung Tel: 886-7-213-7830

Fax: 886-7-330-9305

Taiwan - Taipei

Tel: 886-2-2500-6610 Fax: 886-2-2508-0102

Thailand - Bangkok Tel: 66-2-694-1351

Fax: 66-2-694-1350

EUROPE

Austria - Wels

Tel: 43-7242-2244-39 Fax: 43-7242-2244-393

Denmark - Copenhagen

Tel: 45-4450-2828 Fax: 45-4485-2829

France - Paris

Tel: 33-1-69-53-63-20 Fax: 33-1-69-30-90-79

Germany - Munich

Tel: 49-89-627-144-0 Fax: 49-89-627-144-44

Italy - Milan

Tel: 39-0331-742611 Fax: 39-0331-466781

Netherlands - Drunen

Tel: 31-416-690399 Fax: 31-416-690340

Spain - Madrid

Tel: 34-91-708-08-90 Fax: 34-91-708-08-91 **UK - Wokingham**

Tel: 44-118-921-5869 Fax: 44-118-921-5820

08/04/10